Se	earch Notes		

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/813,774	CHAN ET AL.	
Examiner	Art Unit	
Andrew Wendell	2618	

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SEARCH NOT (INCLUDING SEARCH		')
	DATE	EXMR
East Search	4/4/2006	a,w.
East Search	4/7/2006	۵،٤٠
East Search	4/11/2006	a.w.